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APPLICANTS

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** CONTINUING DATA ***** *NONE* *VB*

** FOREIGN APPLICATIONS ***** *VERIFIED* *JB*
 JAPAN 2002-305157 10/18/2002

IF REQUIRED, FOREIGN FILING LICENSE GRANTED **
 02/17/2004

Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR COUNTRY JAPAN	SHEETS DRAWING 17	TOTAL CLAIMS 26	INDEPENDENT CLAIMS 2
35 USC 119 (a-d) conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance				
Verified and Acknowledged <i>[Signature]</i> Examiner's Signature _____ Initials _____				

ADDRESS

22852

TITLE

Method and apparatus for determining defect detection sensitivity data, control method of defect detection apparatus, and method and apparatus for detecting defect of semiconductor devices

FILING FEE RECEIVED 1442	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:	<input type="checkbox"/> All Fees
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